

Microscopy of semiconducting materials, 1981 - proceedings of the Royal Microscopical Society Conference held in St. Catherines College, Oxford, 6-10 April 1981

The Institute of Physics - Electron optics and electron microscopy: Conference proceedings and abstracts as source material

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Notes: Includes bibliographical references and index.

This edition was published in 1981

Tags: #Monte #Carlo #modeling #for #electron #microscopy #and #microanalysis



Filesize: 58.37 MB

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